Search	<b>Notes</b>

- 1   0   0   1   1   1   1   1   1   1
- 1
- 1 1 8 8 1 8 1 1 1 1 1 1 1 1 1 1 1 1 1
- 1 CB B4B2 31811 BB111 BB13B 16B4B B1111 B611B 18181 16B1 16B1
- 1 ) B B   B   1   B   1   B   B   B   B   B
- 1 1:4 0) 0 : 1   0   1   0   1   1   0   1   1   1

Application/Control No.	Applicant(s)/Patent under Reexamination
10/026,091	FORREST ET AL.
Examiner	Art Unit
Marie R. Yamnitzky	1774

SEARCHED			
Class	Subclass	Date	Examiner
250	200, 215	6/2/2005	MRY
136	243, 252		
	263		
257	184, 431		
	449, 461		
	464		
313	523, 540		
428	411.1		
	458, 469		
	913, 212	<del></del>	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		-	
			,

(INCLUDING SEARCH	STRATEGY	)
	DATE	EXMR
see "SRFW (01/05/20005)" in eDAN file.	6/2/2005	MRY
USPTO STIC Translation Branch - Akiko Smith - partial oral translation of JP 63-300576.	6/2/2005	MRY